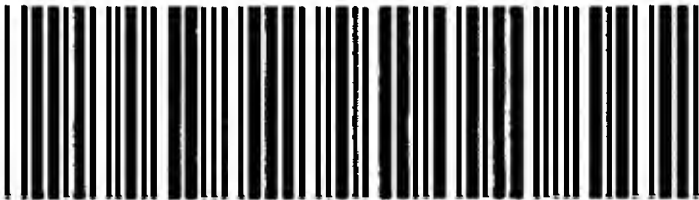


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,934	CHEN ET AL.	
	Examiner	Art Unit	
	David Mis	2817	

SEARCHED			
Class	Subclass	Date	Examiner
331	1A, 10, 11,	12/7/2005	DM
	16, 18,		
	25		
327	156-159		
332	127		
360	51		
375	376		
455	260		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR